

Amendments In The Specification

- ☞ Page 1, please replace the original heading **Reference to Related Application** with the new heading and additional paragraph:

Reference To Related Applications

PAT 6,785,622

This is a division of co-pending Application S/N 10/020,673 filed 29 October 2001 by Richard

A. Nygaard JR and entitled METHOD AND APPARATUS FOR PERFORMING EYE DIAGRAM MEASUREMENTS. --

- ☞ Page 1, please replace the first full original paragraph (after the title and original heading) with:

-- The subject matter of the present Application includes a transition detection circuit usable in a logic analyzer adapted to perform eye diagram measurements, or in a stand-alone circuit for that purpose. And although we disclose herein the general nature of such a detector in sufficient detail to allow a complete understanding of the invention, the actual circuit has complexity beyond what is needed here and is capable of performing additional functions. That actual circuit is the subject matter of a US Patent Application 6,463,392 entitled System and Method for Adjusting a Sampling Time in a Logic Analyzer, of S/N 09/375,307, filed on 16 August 1999 by Richard A. Nygaard et. al, issued 8 October 2002 and assigned to Agilent Technologies, Inc. Because the subject matter of that Application is of interest to that of the present invention, and for the sake of brevity herein, "System and Method for Adjusting a Sampling Time in a Logic Analyzer" is hereby expressly incorporated herein by reference. --;

- ☞ Pages 3 & 4, please replace the first full paragraph beginning on page 3 (and ending on page 4) with:

-- A logic analyzer can be equipped to perform eye diagram measurements by equipping each SUT clock signal input and each SUT data signal input channel with individually variable delays in their respective signal paths. If the range of signal delay is, say, n-many SUT clock cycles, then the SUT